

106.3 Thin Films for X-Ray Fluorescence

This SRM is for standardizing x-ray spectrometers. It may be useful in elemental analysis of particulate matter collected on filter media, and where x-ray spectrometer calibration functions are determined using

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PLEASE NOTE: The tables are presented to facilitate comparisons among a family of materials to help customers select the best SRM for their needs. For specific values and uncertainties, the certificate is the only official source.

Elemental Composition (in $\mu\text{g}/\text{cm}^2$)							
SRM	Description	Fe	Pb	K	Si	Ti	Zn
1833	Thin Glass Film	- Discontinued-					